

DRAM MODULE

1 MEG, 2 MEG x 32

4, 8 MEGABYTE, 5V, FAST PAGE OR EDO PAGE MODE

FEATURES

- JEDEC- and industry-standard pinout in a 72-pin, single-in-line memory module (SIMM)
- · High-performance CMOS silicon-gate process.
- Single +5V ±10% power supply
- All device pins are TTL-compatible
- Low power, 48mW standby; 1,824mW active, typical (8MB)
- Refresh modes: RAS ONLY, CAS-BEFORE-RAS (CBR) and HIDDEN
- Multiple RAS lines allow x16 or x32 width
- · 1,024-cycle refresh distributed across 16ms
- FAST PAGE MODE (FPM) operating mode or Extended Data-Out (EDO) PAGE MODE operating mode

OPTIONS • Timing 60ns access 70ns access (FAST PAGE MODE only) • Packages 72-pin SIMM 72-pin SIMM (gold) • Operating Modes FAST PAGE MODE Blank

KEY TIMING PARAMETERS

EDO Operating Mode

EDO PAGE MODE

ĺ	SPEED	tRC	^t RAC	¹PC	¹ AA	†CAC	tCAS
	-6	110ns	60ns	26ns	30ns	17ns	13ns

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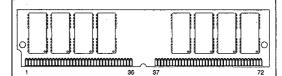
FPM Operating Mode

SPEED	^t RC	^t RAC	· tPC	1AA	1CAC	tRP
-6	110ns	60ns	35ns	30ns	15ns	40ns
-7	130ns	70ns .	40ns	35ns	20ns	50ns

PIN ASSIGNMENT (Front View)

72-Pin SIMM

(DD-3) 1 Meg x 32 (DD-4) 2 Meg x 32



PIN#	SYMBOL	PIN#	SYMBOL	PIN#	SYMBOL	PIN#	SYMBOL
1	Vss	19	NC	37	NC	55	DQ12
2	DQ1	20	DQ5	38	NC	56	DQ28
3	DQ17	21	DQ21	39	Vss	57	DQ13
4	DQ2	22	DQ6	40	CASO	58	DQ29
5	DQ18	23	DQ22	41	CAS2	59	Vcc
6	DQ3	24	DQ7	42	CAS3	60	DQ30
7	DQ19	25	DQ23	43	CAS1	61	DQ14
8	DQ4	26	DQ8	44	RAS0	62	DQ31
9	DQ20	27	DQ24	45	NC*/RAS1	63	DQ15
10	Vcc	28	A7	46	NC	64	DQ32
11	NC	29	NC	47	WE	65	DQ16
12	. A0	30	Vcc	48	NC	66	NC
13	A1	31	A8	49	DQ9	67	PRD1
14	A2	32	A9	50	DQ25	68	PRD2
15	A3	33	NC*/RAS3	51	DQ10	69	PRD3
16	A4	34	RAS2	52	DQ26	70	PRD4
17	A5	35	NC	53	DQ11	71	NC
18	A6	36	NC	54	DQ27	72	Vss

^{*4}MB version only

PART NUMBERS

EDO Operating Mode

PART NUMBER	DESCRIPTION
MT8D132G-xx X	1 Meg x 32, EDO, Gold
MT8D132M-xx X	1 Meg x 32, EDO, Tin/Lead
MT16D232G-xx X	2 Meg x 32, EDO, Gold
MT16D232M-xx X	2 Meg x 32, EDO, Tin/Lead

xx = speed

FPM Operating Mode

PART NUMBER	DESCRIPTION
MT8D132G-xx	1 Meg x 32, Gold
MT8D132M-xx	1 Meg x 32, Tin/Lead
MT16D232G-xx	2 Meg x 32, Gold
MT16D232M-xx	2 Meg x 32, Tin/Lead

xx = speed

GENERAL DESCRIPTION

The MT8D132(X) and MT16D232(X) are randomly accessed 4MB and 8MB solid-state memories organized in a x32 configuration. During READ or WRITE cycles each bit is uniquely addressed through the 20 address bits, which are entered 10 bits (A0-A9) at a time. RAS is used to latch the first 10 bits and CAS the latter 10 bits. A READ or WRITE cycle is selected with the WE input. A logic HIGH on WE dictates READ mode while a logic LOW on WE dictates WRITE mode. During a WRITE cycle, data-in (D) is latched by the falling edge of WE or CAS, whichever occurs last. EARLY WRITE occurs when WE goes LOW prior to CAS going LOW, the output pin(s) remain open (High-Z) until the next CAS cycle.

FAST PAGE MODE

FAST PAGE MODE operations allow faster data operations (READ or WRITE) within a row-address-defined (A0-A9) page boundary. The FAST PAGE MODE cycle is always initiated with a row-address strobed-in by RAS followed by a column-address strobed-in by CAS. CAS may be toggled-in by holding RAS LOW and strobing-in different column-addresses, thus executing faster memory cycles. Returning RAS HIGH terminates the FAST PAGE MODE operation.

EDO PAGE MODE

EDO PAGE MODE, designated by the "X" version, is an accelerated FAST PAGE MODE cycle. The primary advantage of EDO is the availability of data-out even after CAS goes back HIGH. EDO provides for CAS precharge time (^tCP) to occur without the output data going invalid. This elimination of CAS output control provides for pipeline READs.

FAST PAGE MODE modules have traditionally turned the output buffers off (High-Z) with the rising edge of CAS. EDO operates as any DRAM READ or FAST-PAGE-MODE READ, except data will be held valid after CAS goes HIGH, as long as RAS and OE are held LOW and WE is held HIGH (reference MT4C4007] DRAM data sheet for additional information on EDO functionality).

REFRESH

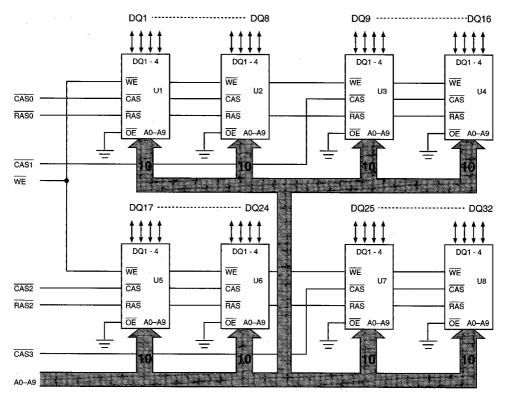
Returning RAS and CAS HIGH terminates a memory cycle and decreases chip current to a reduced standby level. Also, the chip is preconditioned for the next cycle during the RAS HIGH time. Memory cell data is retained in its correct state by maintaining power and executing any RAS cycle (READ, WRITE) or RAS refresh cycle (RAS ONLY, CBR or HIDDEN) so that all 1,024 combination of RAS addresses (A0-A9) are executed at least every 16ms, regardless of sequence.

x16 CONFIGURATION

For x16 applications, the corresponding DQ and \overline{CAS} pins must be connected together (DQ1 to DQ17, DQ2 to DQ18 and so forth, and CASO to CASO and CASO to $\overline{\text{CAS3}}$). Each $\overline{\text{RAS}}$ is then a bank select for the x16 memory organization.



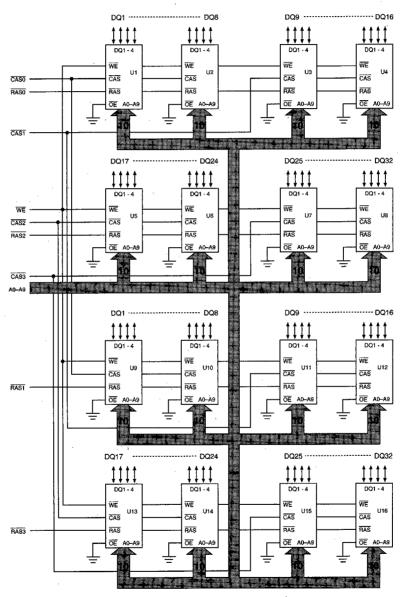
FUNCTIONAL BLOCK DIAGRAM MT8D132(X) (4MB)



FAST PAGE MODE U1-U8 = MT4C4001JDJ

EDO PAGE MODE U1-U8 = MT4C4007JDJ

FUNCTIONAL BLOCK DIAGRAM MT16D232(X) (8MB)



FAST PAGE MODE U1-U16 = MT4C4001J

EDO PAGE MODE U1-U16 = MT4C4007JDJ



TRUTH TABLE

			ADDR	ESSES	DATA-IN/OUT		
FUNCTION		RAS	CAS	WE	t _R	^t C	DQ1-DQ32
Standby		Н	H→X	Х	Х	X	High-Z
READ		L	L	Н	ROW	COL	Data-Out
EARLY WRITE		L	L	L	ROW	COL	Data-In
EDO/FAST-PAGE-	1st Cycle	L	H→L	Н	ROW	COL	Data-Out
MODE READ 2nd Cv		L	H→L	Н	n/a	COL	Data-Out
•	Any Cycle (X version)	L	L→H	Н	n/a	n/a	Data-Out
EDO/FAST-PAGE-	1st Cycle	L	H→L	L	ROW	COL	Data-In
MODE EARLY WRITE	2nd Cycle	L	H→L	L	n/a	COL	Data-In
RAS-ONLY REFRESH		L	Н	Х	ROW	n/a	High-Z
HIDDEN	READ	L→H→L	L	Н	ROW	COL	Data-Out
REFRESH	WRITE	L→H→L	L	L	ROW	COL	Data-In
CBR REFRESH		H→L	L	Н	Х	Х	High-Z

JEDEC DEFINED PRESENCE-DETECT - MT8D132(X) (4MB)

SYMBOL	PIN#	-6	-7
PRD1	67	Vss	Vss
PRD2	68	Vss	Vss
PRD3	69	NC	Vss
PRD4	70	NC	NC

JEDEC DEFINED PRESENCE-DETECT - MT16D232(X) (8MB)

SYMBOL	PIN#	-6	-7
PRD1	67	NC	NC
PRD2	68	NC	NC
PRD3	69	NC	Vss
PRD4	70	NC	NC

ABSOLUTE MAXIMUM RATINGS*

Voltage on Vcc Supply Relative to Vss	1V to +7V
Operating Temperature, TA (ambient).	
Storage Temperature (plastic)	
Power Dissipation	8W
Short Circuit Output Current	

*Stresses greater than those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

ELECTRICAL CHARACTERISTICS AND RECOMMENDED DC OPERATING CONDITIONS

(Notes: 1, 3, 6) ($Vcc = +5V \pm 10\%$)

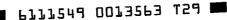
PARAMETER/CONDITION		SYMBOL	MIN	MAX	UNITS	NOTES
Supply Voltage		Vcc	4.5	5.5	V	,
Input High (Logic 1) Voltage, all inputs		ViH	2.4	Vcc+1	V	
Input Low (Logic 0) Voltage, all inputs		VIL	-1.0	0.8	V	
INPUT LEAKAGE CURRENT	CASO-CAS3	[H	-8	8	μА	-:
Any input 0V ≤ Vin ≤ Vcc +1.0V	A0-A9, WE	, l ı2	-32	32	μA	25
(All other pins not under test = 0V)	RAS0-RAS3	· li3	-8	8	μΑ	25
OUTPUT LEAKAGE CURRENT (Q is disabled; $0V \le Vout \le 5.5V$)	DQ1-DQ32	loz	-20	20	μΑ	25
OUTPUT LEVELS	-	Vон	2.4		٧	
High Voltage (Ioυτ = -5mA)		Vol		0.4	٧	
Low Voltage (lout = 4.2mA)						

			M	AX]	
PARAMETER/CONDITION	SYMBOL	SIZE	-6	-7	UNITS	NOTES
STANDBY CURRENT: (TTL) (RAS = CAS = VIH)	Icc1	4MB 8MB	16 32	16 32	mA	
STANDBY CURRENT: (CMOS) (RAS = CAS = other inputs = Vcc -0.2V)	lcc2	4MB 8MB	8 16	8 16	mA	
OPERATING CURRENT: Random READ/WRITE Average power supply current (RAS, CAS, address cycling: [†] RC = [†] RC [MIN])	lccs	4MB 8MB	880 896	800 816	mA	2, 24
OPERATING CURRENT: FAST PAGE MODE Average power supply current (RAS = VIL, CAS, address cycling: \text{VPC} = \text{VPC} [MIN])	Icc4	4MB 8MB	640 656	560 576	mA	2, 24
OPERATING CURRENT: EDO PAGE MODE Average power supply current (RAS = V _{IL} , CAS, address cycling: ^t PC = ^t PC [MIN])	lccs (X only)	4MB 8MB	640 656	_	mA	2
REFRESH CURRENT: RAS ONLY Average power supply current (RAS cycling, CAS = VIH: RC = RC [MIN])	Icce	4MB 8MB	880 896	800 816	mA	2, 24
REFRESH CURRENT: CBR Average power supply current (RAS, CAS, address cycling: ^t RC = ^t RC [MIN])	lcc7	4MB 8MB	880 896	800 816	mA	2, 19

MT8D132(X), MT16D232(X) DM53.pm5 - Rev. 12/95

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CAPACITANCE		М	AX]	
PARAMETER	SYMBOL	4MB	8MB	UNITS	NOTES
Input Capacitance: A0-A9	C _{I1}	48	95	pF	17
Input Capacitance: WE	Cl2	64	127	pF	17
Input Capacitance: RAS0-RAS3	C14	32	32	pF	17
Input Capacitance: CAS0-CAS3	C ₁₅	16	32	pF	17
Input/Output Capacitance: DQ1-DQ32	Cio	10	18	pF	17

FAST PAGE MODE ELECTRICAL CHARACTERISTICS AND RECOMMENDED AC OPERATING CONDITIONS

(Notes: 3, 4, 5, 6, 7, 10, 11, 16) ($Vcc = +5V \pm 10\%$)

AC CHARACTERISTICS - FAST PAGE MODE OPTION	DE OPTION		6	-7			
PARAMETER	SYM	MIN	MAX	MIN	MAX	UNITS	NOTES
Access time from column-address	tAA .		30		35	ns	
Column-address hold time (referenced to RAS)	^t AR	45		50		ns	
Column-address setup time	†ASC	0		0		ns	
Row-address setup time	tASR	0		0		пѕ	
Access time from CAS	^t CAC		15		20	ns	9
Column-address hold time	^t CAH	10		15		ns	
CAS pulse width	†CAS	15	10,000	20	10,000	ns	
CAS hold time (CBR REFRESH)	tCHR	10		10		ns	19
CAS to output in Low-Z	†CLZ	0		0		ns	
CAS precharge time	¹ CP	10		10		ns	18
Access time from CAS precharge	¹CPA		35		40	ns	
CAS to RAS precharge time	^t CRP	10		10		ns	
CAS hold time	^t CSH	60		70		ns	
CAS setup time (CBR REFRESH)	¹ CSR	10		10		ns	19
Write command to CAS lead time	tCWL	15		20		ns	
Data-in hold time	tDH	10		15		ns	15
Data-in hold time (referenced to RAS)	[†] DHR	45		55		ns	
Data-in setup time	†DS	. 0		0		ns	15
Output buffer turn-off delay	†OFF	3	15	3	20	ns	12, 23, 2
FAST-PAGE-MODE READ or WRITE cycle time	^t PC	35		40		ns	
Access time from RAS	tRAC		60		70	ns	8
RAS to column-address delay time	†RAD	15	30	15	35	ns	22
Row-address hold time	†RAH	10		10		ns	
Column-address to RAS lead time	^t RAL	30		35		ns	
RAS pulse width	†RAS	60	10,000	70	10,000	ns	
RAS pulse width (FAST PAGE MODE)	†RASP	60	100,000	70	100,000	ns	
Random READ or WRITE cycle time	^t RC	110		130		ns	
RAS to CAS delay time	†RCD	20	45	20	50	ns	13
Read command hold time (referenced to CAS)	†RCH	0		0		ns	14
Read command setup time	t _{RCS}	0		0		ns	
Refresh period (1,024 cycles)	tREF.		16		16	ms	



FAST PAGE MODE ELECTRICAL CHARACTERISTICS AND RECOMMENDED AC OPERATING CONDITIONS

(Notes: 3, 4, 5, 6, 7, 10, 11, 16) ($Vcc = +5V \pm 10\%$)

AC CHARACTERISTICS - FAST PAGE MODE OPTION			-6		-7	,	
PARAMETER	SYM	MIN	MAX	MIN	MAX	UNITS	NOTES
RAS precharge time	t _{RP}	40		50	<u> </u>	ns	
RAS to CAS precharge time	^t RPC	0		0		ns	
Read command hold time	^t RRH	0		0		ns	14
RAS hold time	tRSH	15		20		ns	
Write command to RAS lead time	tRWL	15		20		ns	
Transition time (rise or fall)	ţΤ	3	50	3	50	ns	-
Write command hold time	†WCH	10	1	15		ns	
Write command hold time (referenced to RAS)	†WCR	45		55		ns	
WE command setup time	†WCS	0	İ	0	<u> </u>	ns	
Write command pulse width	^t WP	10	,	15		ns	
WE hold time (CBR REFRESH)	[†] WRH	10		10		ns	
WE setup time (CBR REFRESH)	¹WRP	10		10		ns	



EDO PAGE MODE ELECTRICAL CHARACTERISTICS AND RECOMMENDED AC OPERATING CONDITIONS

(Notes: 3, 4, 5, 6, 7, 10, 11, 16) (Vcc = +5V ±10%)

AC CHARACTERISTICS - EDO PAGE MODE OPTION			-6		
PARAMETER	SYM	MIN	MAX	UNITS	NOTES
Access time from column-address	t _{AA}		30	ns	
Column-address setup to CAS precharge during WRITE	¹ ACH	15		ns	
Column-address hold time (referenced to RAS)	tAR .	45		ns	
Column-address setup time	tASC	0		ns ·	
Row-address setup time	tasr.	0		ns	
Access time from CAS	†CAC		17	ns	9
Column-address hold time	^t CAH	10		ns	
CAS pulse width	^t CAS	13	10,000	ns	
CAS hold time (CBR REFRESH)	tCHR	10		пѕ	19
CAS to output in Low-Z	tCLZ	3		. ns	23
Data output hold after CAS LOW	tCOH	5		ns	
CAS precharge time	[†] CP	10		ns	18
Access time from CAS precharge	†CPA		35	ns .	
CAS to RAS precharge time	¹CRP	10		ns	
CAS hold time	†CSH	50		ns	
CAS setup time (CBR REFRESH)	†CSR	10		ns	19
Write command to CAS lead time	tCWL	15		ns	
Data-in hold time	tDH	9		ns	15
Data-in hold time (referenced to RAS)	^t DHR	45		ns	1
Data-in setup time	^t DS	0		ns	15
Output buffer turn-off delay	[†] OFF	3	15	ns	12, 23, 2
FAST-PAGE-MODE READ or WRITE cycle time	· tPC	26		ns	
Access time from RAS	^t RAC		60	ns	8
RAS to column-address delay time	^t RAD	15	30	ns	22
Row-address hold time	^t RAH	10		ns	
Column-address to RAS lead time	^t RAL	30		ns	
RAS pulse width	^t RAS	60	10,000	ns	
RAS pulse width (FAST PAGE MODE)	†RASP	.60	100,000	ns	
Random READ or WRITE cycle time	^t RC	110		ns	
RAS to CAS delay time	†RCD	20	45	ns	13
Read command hold time (referenced to CAS)	^t RCH	0		ns	14
Read command setup time	tRCS	0		ns	1
Refresh period (1,024 cycles)	¹REF		16	ms	

EDO PAGE MODE

ELECTRICAL CHARACTERISTICS AND RECOMMENDED AC OPERATING CONDITIONS

(Notes: 3, 4, 5, 6, 7, 10, 11, 16) ($Vcc = +5V \pm 10\%$)

AC CHARACTERISTICS - EDO PAGE MODE OPTION			-6		
PARAMETER	SYM	MIN	MAX	UNITS	NOTES
RAS precharge time	tRP	40		ns	
RAS to CAS precharge time	tRPC	5		ns	
Read command hold time	†RRH	0		ns	14
RAS hold time	^t RSH	15		ns	
Write command to RAS lead time	t _{RWL}	15		ns	
Transition time (rise or fall)	ŀΤ	1.5	50	ns	4, 5
Write command hold time	†WCH	10		ns	
Write command hold time (referenced to RAS)	¹WCR	45		ns	
WE command setup time	¹wcs	0		ns	
Output disable delay from WE (CAS HIGH)	^t WHZ	3	15	ns .	
Write command pulse width	†WP	10		ns	
WE pulse width for output disable when CAS HIGH	†WPZ	10		ns	***************************************
WE hold time (CBR REFRESH)	^t WRH	10	·.	nş	
WE setup time (CBR REFRESH)	tWRP	10		ns	

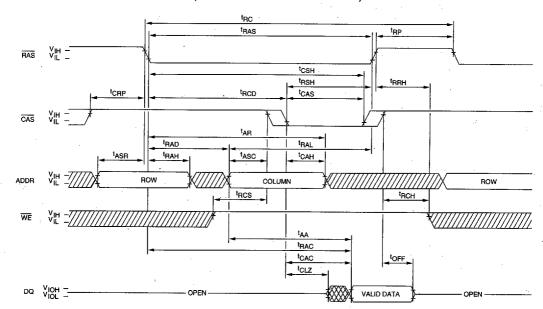


NOTES

- 1. All voltages referenced to Vss.
- Icc is dependent on output loading and cycle rates. Specified values are obtained with minimum cycle time and the output open.
- 3. An initial pause of 100µs is required after power-up followed by eight RAS refresh cycles (RAS ONLY or CBR with WE HIGH) before proper device operation is assured. The eight RAS cycle wake-ups should be repeated any time the ^tREF refresh requirement is exceeded.
- AC characteristics assume ^tT = 5ns for FAST PAGE MODE and ^tT = 1.5ns for EDO PAGE MODE.
- VIH (MIN) and VIL (MAX) are reference levels for measuring timing of input signals. Transition times are measured between VIH and VIL.
- The minimum specifications are used only to indicate cycle time at which proper operation over the full temperature range (0°C ≤ T_A ≤ 70°C) is assured.
- 7. Measured with a load equivalent to two TTL gates and 100pF.
- Assumes that ^tRCD < ^tRCD (MAX). If ^tRCD is greater than the maximum recommended value shown in this table, ^tRAC will increase by the amount that ^tRCD exceeds the value shown.
- Assumes that [†]RCD ≥ [†]RCD (MAX).
- 10. If $\overline{\text{CAS}}$ and $\overline{\text{RAS}}$ = V_{IH}, data output is High-Z.
- If CAS = VIL, data output may contain data from the last valid READ cycle.
- OFF (MAX) defines the time at which the output achieves the open circuit condition and is not referenced to VOH or VOL.
- 13. Operation within the ^tRCD (MAX) limit ensures that ^tRAC (MAX) can be met. ^tRCD (MAX) is specified as a reference point only; if ^tRCD is greater than the specified ^tRCD (MAX) limit, then access time is controlled exclusively by ^tCAC.

- Either ^tRCH or ^tRRH must be satisfied for a READ cycle.
- 15. These parameters are referenced to $\overline{\text{CAS}}$ leading edge in EARLY WRITE cycles.
- 16. In addition to meeting the transition rate specification, all input signals must transit between VIII and VIII. (or between VIII and VIII) in a monotonic manner.
- 17. This parameter is sampled. Capacitance is measured using MIL-STD-883C, Method 3012.1 (1 MHz AC, Vcc = 4.5V, DC bias = 2.4V at 15mV RMS).
- 18. If CAS is LOW at the falling edge of RAS, data-out (Q) will be maintained from the previous cycle. To initiate a new cycle and clear the data-out buffer, CAS must be pulsed HIGH for ^tCP.
- 19. On-chip refresh and address counters are enabled.
- 20. A HIDDEN REFRESH may also be performed after a WRITE cycle. In this case, WE = LOW.
- 21. LATE WRITE, READ WRITE or READ-MODIFY-WRITE cycles are not available due to OE being grounded on U1-U8/U16.
- 22. Operation within the ^tRAD (MAX) limit ensures that ^tRCD (MAX) can be met. ^tRAD (MAX) is specified as a reference point only; if ^tRAD is greater than the specified ^tRAD (MAX) limit, then access time is controlled exclusively by ^tAA.
- 23. The 3ns minimum is a parameter guaranteed by design.
- 24. Column-address changed once each cycle.
- 25. 4MB module values will be half of those shown.
- 26. For FAST PAGE MODE option, ^tOFF is determined by the first RAS or CAS signal to transition HIGH. In comparison, ^tOFF on an EDO option is determined by the latter of the RAS and CAS signal to transition HIGH.
- 27. Applies to both EDO and FAST PAGE MODEs.

READ CYCLE (FAST PAGE MODE Module)



DON'T CARE

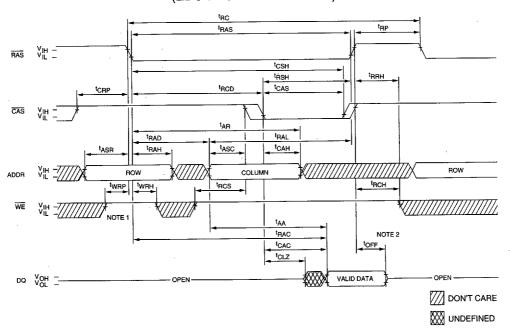
UNDEFINED

FAST PAGE MODE TIMING PARAMETERS

		-6	-7		
SYM	MIN	MAX	MIN	MAX	UNITS
^t AA		30		35	ns
^t AR	45		50		ns
tASC	0		0		ns
^t ASR	0		0		ns
tCAC		15		20	ns
^t CAH	10		15		ns
[†] CAS	15	10,000	20	10,000	ns
†CLZ	0	T	0	1.	ns
^t CRP	10		10		ns
^t CSH	60		70		ns
^t OFF	3	15	3	20	ns
^t RAC		60		70	ns

	-6		-7		
SYM	MIN	MAX	MIN	MAX	UNITS
^t RAD	15	30	15	35	ns
^t RAH	10		10		ns
^t RAL	30		35		ns
^t RAS	60	10,000	70	10,000	ns
^t RC	110		130		ns
^t RCD	20	45	20	50	ns
^t RCH	0		0	1	ns
^t RCS	0		0		ns
†RP	40		50		ns
^t RRH	0		0		ns
[†] RSH	15		20		ns

READ CYCLE (EDO PAGE MODE Module)



NOTE:

- 1. Although WE is a "don't care" at RAS time during an access cycle (READ or WRITE), the system designer should implement WE HIGH for WRP and WRH. This design implementation will facilitate compatibility with future EDO DRAMs.
- 2. OFF is referenced from rising edge of RAS or CAS, whichever occurs last.

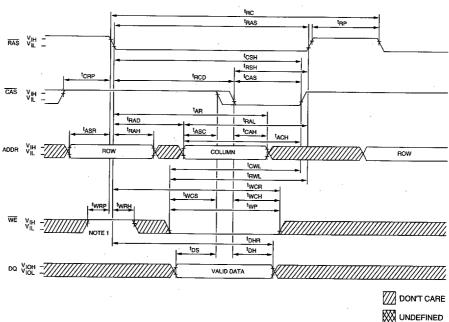
EDO PAGE MODE TIMING PARAMETERS

		-6	
SYM	MIN	MAX	UNITS
†AA		30	ns
^t AR	45		ns
¹ ASC	0		ns
^t ASR	0		ns
¹CAC		17	ns
^t CAH	10		ns
^t CAS	13	10,000	ns
^t CLZ	3		ns
¹ CRP	. 10		ns
¹CSH	50		ns
^t OFF	3	15	ns
^t RAC		60	ns
^t RAD	15	30	ns

SYM	MIN	MAX	UNITS
^t RAH	10		ns
^t RAL	30		ns
^t RAS	60	10,000	ns
^t RC	110		ns
^t RCD	20	45	ns
^t RCH	0		ns
†RCS	0		ns
^t RP	40		ns
^t RRH	0		ns
^t RSH	15		ns
tWRH	10		ns
†WRP	10		ns

MT8D132(X), MT16D232(X) DM53.pm5 - Rev. 12/95

EARLY WRITE CYCLE 27



NOTE:

1. Although WE is a "don't care" at RAS time during an access cycle (READ or WRITE), the system designer should implement WE HIGH for WRP and WRH. This design implementation will facilitate compatibility with future EDO DRAMs.

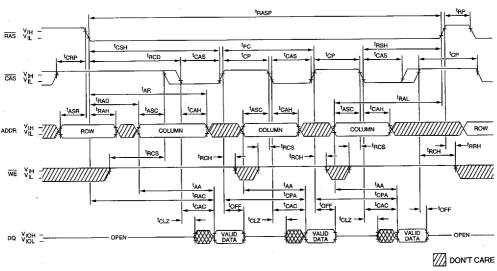
FAST PAGE MODE AND EDO PAGE MODE TIMING PARAMETERS

	-6		-7		
SYM	MIN	MAX	MIN	MAX	UNITS
tACH (EDO)	15				ns
^t AR	45		50		ns
tASC	0		0		ns
^t ASR	0		0		ns
[†] CAH	10		15		ns
^t CAS (FPM)	15	10,000	20	10,000	ns
^t CAS (EDO)	13	10,000		_	ns
^t CRP	10		10		ns
tCSH (FPM)	60		70		ns
^t CSH (EDO)	50				ns
^t CWL	15		20		ns
[†] DH (FPM)	10		15		ns
^t DH (EDO)	. 9		_		ns
^t DHR	45		55	1	ns
^t D\$	0		0		ns

		-6		-7	
SYM	MIN	MAX	MIN	MAX	UNITS
^t RAD	15	30	15	35	ns
^t RAH	10		10		ns
^t RAL	30		35		ns
†RAS	60	10,000	70	10,000	пѕ
†RC	110		130		ns
[†] RCD	20	45	20	50	'ns
^t RP	40		50		ns
^t RSH	15		20		ns
^t RWL	15		20		ns
tMCH	10		15		ns
^t WCR	45		55		ns.
twcs	0	·	0		ns
[†] WP	10		15		ns
™RH	10		10		ns
tWRP	10		10		ns



FAST-PAGE-MODE READ CYCLE



UNDEFINED

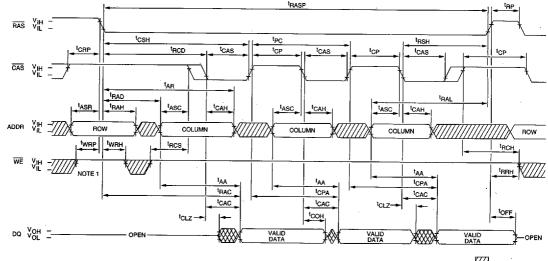
FAST PAGE MODE TIMING PARAMETERS

		-6			
SYM	MIN	MAX	MIN	MAX	UNITS
†AA		30		35	ns
tAR	45		50		ns
^t ASC	0		0		ns
^t ASR	0		0		ns
^t CAC		15		20	ns
^t CAH	10		15		ns
^t CAS	15	10,000	20	10,000	ns
^t CLZ	0		0		ns
^t CP	10		10		ns
^t CPA		35		40	ns
^t CRP	10		10		ns
tCSH	60		70		ns
^t OFF	3	15	3	20	ns

	-6		-7		
SYM	MIN	MAX	MIN	MAX	UNITS
^t PC	35		40		ns
^t RAC		60		70	ns
^t RAD	15	30	15	35	ns
^t RAH	10		10		ns
^t RAL	30		35		ns
†RASP	60	100,000	70	100,000	ns
†RCD	20	45	20	50	ns
^t RCH	0		0		ns
†RCS	0		0		ns
^t RP	40		50		ns
^t RRH	0		0		ns
^t RSH	15		20		ns



EDO-PAGE-MODE READ CYCLE



DON'T CARE

₩ UNDEFINED

NOTE:

1. Although WE is a "don't care" at RAS time during an access cycle (READ or WRITE), the system designer should implement WE HIGH for tWRP and tWRH. This design implementation will facilitate compatibility with future EDO DRAMs.

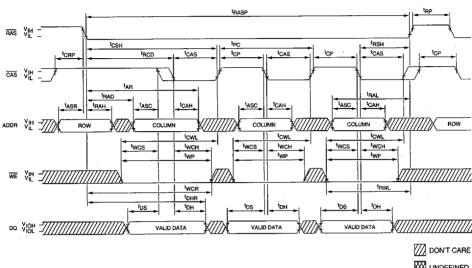
EDO PAGE MODE TIMING PARAMETERS

		-6	
SYM	MIN	MAX	UNITS
^t AA		30	ns
^t AR	45		ns
tASC :	. 0		ns
^t ASR	0		ns
^t CAC		17	ns
^t CAH	10		ns
^t CAS	13	10,000	ns
†CLZ	3		ns
[†] COH	5		ns
[†] CP	10		ns
^t CPA		35	ns
[†] CRP	10		ns
^t CSH	50		ns
^t OFF	3	15	ns

		-6	
SYM	MIN	MAX	UNITS
^t PC	26		ns
†RAC		60	ns
[†] RAD	15	30	ns
^t RAH	10		ns
^t RAL	30	١,	ns
tRASP	60	100,000	ns
^t RCD	20	45	ns
^t RCH	0		ns
^t RCS	0		ns -
^t RP	40		ns
^t RRH	0		ns
^t RSH	15		ns
tWRH	10		ns
tWRP	10		ns



FAST-PAGE-MODE EARLY-WRITE CYCLE



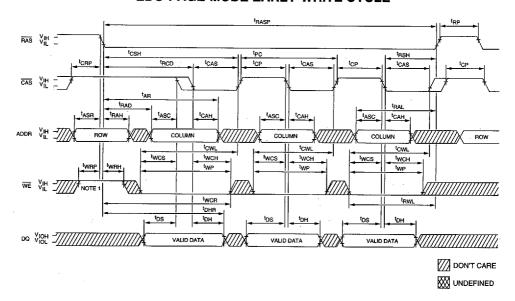
W UNDEFINED

FAST PAGE MODE TIMING PARAMETERS

		-6		-7	
SYM	MIN	MAX	MIN	MAX	UNITS
^t AR	45		50		ns
†ASC	0		0		ns
tASR	0	1	0		ns
^t CAH	10		15		ns
tCAS	15	10,000	20	10,000	ns
^t CP	10		10		ns
^t CRP	10		10		ns
¹ CSH	60		70	· · · · · · · · · · · · · · · · · · ·	ns
^t CWL	15		20		ns
¹DH	10		15		ns
^t DHR	45		55		ns
^t DS	0		0		ns
^t PC	35		40		ns

	-6		-7		
SYM	MIN	MAX	MIN	MAX	UNITS
^t RAD	15	30	15	35	ns
^t RAH	10		10		ns
^t RAL	30		35		ns
^t RASP	60	100,000	70	100,000	ns
^t RCD	20	45	20	50	ns
^t RP	40		50		ns
^t RSH	15		20		ns
^t RWL	15		20		ns
†WCH	10		15		ns
†WCR	45		55		ns
twcs	0		0		ns
^t WP	10		15		ns

EDO-PAGE-MODE EARLY-WRITE CYCLE



NOTE:

Although WE is a "don't care" at FAS time during an access cycle (READ or WRITE), the system designer should implement
WE HIGH for tWRP and tWRH. This design implementation will facilitate compatibility with future EDO DRAMs.

EDO PAGE MODE TIMING PARAMETERS

		-6	
SYM	MIN	MAX	UNITS
^t AR	45		ns
^t ASC	0		ns
^t ASR	0		ns
^t CAH	. 10		ns
¹ CAS	13	10,000	ns
^t CP	10	,	ns
^t CRP	10		ns
^t CSH	50		ns
tCML	15		ns
^t DH	9	1	ns
^t DHR	45		ns
^t DS	0		ns
^t PC	26		ns
^t RAD	15	30	пѕ

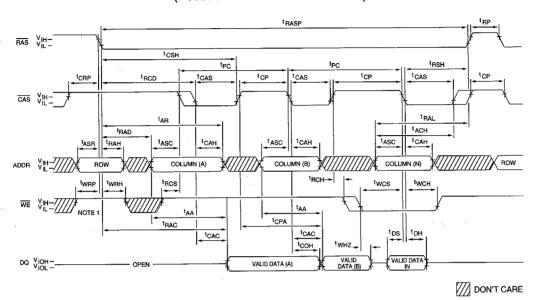
		-6	
SYM	MIN	MAX	UNITS
¹ RAH	10		ns
[†] RAL	30		ns
^t RASP	60	100,000	ns
^t RCD	20	45	ns
^t RP	40		ns
^t RSH	15		ns
^t RWL	. 15		ns
tWCH	10		ns
tWCR	45		ns
†WCS	0		ns
^t WP	10		ns
^t WRH	10		ns
[†] WRP	10		ns

UNDEFINED



EDO-PAGE-MODE READ-EARLY-WRITE CYCLE

(Pseudo READ-MODIFY-WRITE)



NOTE:

1. Although WE is a "don't care" at RAS time during an access cycle (READ or WRITE), the system designer should implement WE HIGH for \(^1\)WRP and \(^1\)WRP. This design implementation will facilitate compatibility with future EDO DRAMs.

EDO PAGE MODE TIMING PARAMETERS

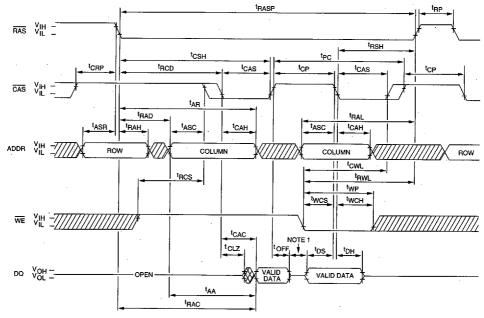
		-6	
SYM	MIN	MAX	UNITS
^t AA		30	ns
^t ACH	15		ns
^t AR	45		ns
^t ASC	0 .		ns
^t ASR	0		ns
^t CAC		17	ns
tCAH	10		ns
tCAS	13	10,000	ns
tCOH	5		ns
^t CP	10		ns
^t CPA		35	ns
^t CRP	10		ns
tCSH	50		ns
^t DH	9		ns
^t DS	. 0		ns
^t PC	26		ns

	T	•	
		-6	
SYM	MIN	MAX	UNITS
^t RAC		60	ns
^t RAD	15	30	ns
^t RAH	10		ns
^t RAL	30		ns
¹ RASP	60	100,000	ns
[†] RCD	20	45	ns
^t RCH	0		ns
tRCS	0		ns
^t RP	40		ns
^t RSH	15		ns
tWCH	. 10		ns
†WCS	0		ns
†WHZ	3	15	ns
†WRH	10		ns
†WRP	. 10		ns



FAST-PAGE-MODE READ-EARLY-WRITE CYCLE

(Pseudo READ-MODIFY-WRITE)



DON'T CARE

NOTE:

1. Do not drive data prior to tristate.

₩ UNDEFINED

FAST PAGE MODE TIMING PARAMETERS

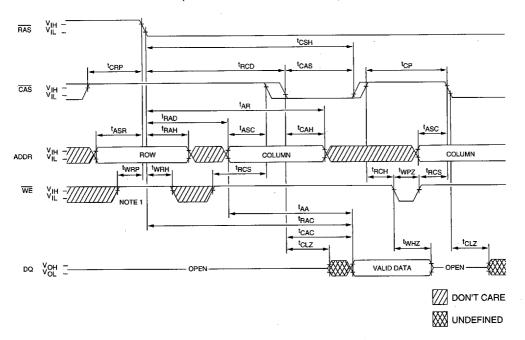
		-6		-7	
SYM	MIN	MAX	MIN	MAX	UNITS
^t AA		30		35	ns
^t AR	45		50		ns
^t ASC	0		0	1	ns
^t ASR	0		0		ns
CAC		15		20	ns
^t CAH	10		15		ns
tCAS	15	10,000	20	10,000	ns
[†] CLZ	0.		0		ns
[†] CP	10		10		ns
[†] CRP	10		10		ns .
^t CSH	60		70		пѕ
tCML	15		20	T .	пѕ
^t DH	10		15		ns
tDS .	0		0		ns
^t OFF	3	15	3	20	ns

		-6		-7	
SYM	MIN	MAX	MIN	MAX	UNITS
^t PC	35		40		ns
^t RAC		60		70	ns
^t RAD	15	30	15	35	ns
^t RAH	10		10		ns
^t RAL	30		35		ns
^t RASP	60	100,000	70	100,000	ns
^t RCD	20	45	20	50	ns
tRCS	0		0		ns
^t RP	40		50		ns
^t RSH	15		20		ns
†RWL	15		20		ns
†WCH	10		15		ns
†WCS	0		0		ns
tWP	10		15		ns



EDO READ CYCLE

(with WE-controlled disable)



NOTE:

1. Although WE is a "don't care" at RAS time during an access cycle (READ or WRITE), the system designer should implement WE HIGH for WRP and WRH. This design implementation will facilitate compatibility with future EDO DRAMs.

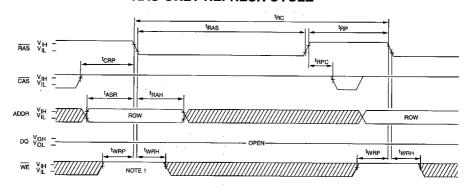
EDO PAGE MODE TIMING PARAMETERS

SYM	MIN	MAX	UNITS
^t AA		30	ns
^t AR	45		ns
†ASC	0		ns
^t ASR	0		ns
^t CAC		17	ns
^t CAH	10		ns
tCAS	13	10,000	ns
^t CLZ	3		ns
^t CP	10		ns
^t CRP	10		пѕ
[†] CSH	50		ns

		6	
SYM	MIN .	MAX	UNITS
†RAC		60	ns
†RAD	15	30	пѕ
^t RAH	10		ns
¹ RCD	20	45	ns
^t RCH	- 0	1	ns
^t RCS	0		ns
tWHZ	3	15	ns
^t WPZ	10		ns
^t WRH	10		ns
[†] WRP	10		ns

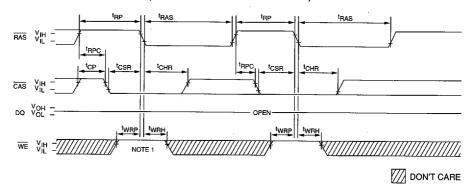


RAS-ONLY REFRESH CYCLE 27



CBR REFRESH CYCLE 29

(Addresses = DON'T CARE)



NOTE:

1. Although WE is a "don't care" at RAS time during an access cycle (READ or WRITE), the system designer should implement WE HIGH for \(^1\)WRP and \(^1\)WRH. This design implementation will facilitate compatibility with future EDO DRAMs.

FAST PAGE MODE AND EDO PAGE MODE TIMING PARAMETERS

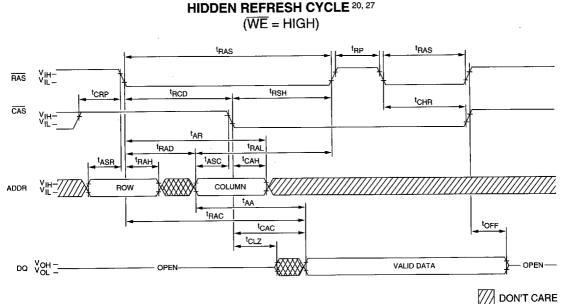
SYM	-6		-7		
	MIN	MAX	MIN	MAX	UNITS
^t ASR	0		0		ns
^t CHR	10		10		ns
¹ CP	10		10		ns
^t CRP	10		10		ns
^t CSR	10		10		ns
^t RAH	10		10		ns
tRAS	60	10,000	70	10,000	ns

	-6		-7		
SYM	MIN	MAX	MIN	MAX	UNITS
^t RC	110		130		ns
^t RP	40		50		ns
tRPC (FPM)	0		0		ns
tRPC (EDO)	5	·			ns
tWRH .	10		10		ns
^t WRP	10		10		ns

UNDEFINED

W UNDEFINED





FAST PAGE MODE AND EDO PAGE MODE TIMING PARAMETERS

	-6		-7		
SYM	MIN	MAX	MIN	MAX	UNITS
^t AA		30		35	ns
^t AR	45	l	50		ns
[†] ASC	0		0		ns
^t ASR	0		0		ns
¹CAC (FPM)		15		20	ns
[†] CAC (EDO)		17		_	ns
^t CAH	10		15		ns
^t CHR	10		10		ns
[†] CLZ	3		3		ns
[†] CRP	10		10		ns

	-6		-7		
SYM	MIN	MAX	MIN	MAX	UNITS
¹OFF	3	15	3	20	ns
^t RAC ·		60		70	ns
†RAD	15	30	15	35	ns
^t RAH	10		10		ns
tRAL.	30		35		ns
^t RAS	60	10,000	70	10,000	пѕ
^t RCD	20	45	20	50	ns
^t RP	40		50		ns
^t RSH	15		20		nş